

# Search Notes



Application/Control No.

10/510,501

Examiner

Sang Y. Paik

Applicant(s)/Patent under  
Reexamination

SHIMIZU ET AL.

Art Unit

3742

## SEARCHED

Class	Subclass	Date	Examiner
392	386		
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	438		
	429		
	432		
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239	34		
	35		
422	5		
	125	9/18/05	20

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
CPST 76A JAPANESE	9/18/05	X